

## Reactive ion etching of 4H-SiC using SF<sub>6</sub>/O<sub>2</sub> for MEMS application

### ABSTRACT

Deep Reactive Ion Etching (DRIE) of 4H-SiC performed using SF<sub>6</sub>/O<sub>2</sub> plasma. The etching rates investigated as a function of the ratio of the O<sub>2</sub> flow rate to total gas flow rate under different etching conditions such as the effect of power density, temperature, and the combination of chemistries on etching. The investigation was proven that the contribution and effect of the direct role of Oxygen to deep etching of SiC. An optimum value of O<sub>2</sub> fraction of 60% to 40% Sulfur Hexafluoride (SF<sub>6</sub>) used to give high etching rate of 1.2µm/min. for maximum etching.

**Keyword:** Deep Reactive Ion Etching (DRIE); Sulfur hexafluoride (SF<sub>6</sub>); 4H-SiC; Plasma